



FOR IMMEDIATE RELEASE

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**AEHR TEST SYSTEMS ANNOUNCES \$2.5 MILLION IN ORDERS FROM LEADING IC MANUFACTURER**

**Fremont, CA (July 26, 2013) - Aehr Test Systems (Nasdaq: AEHR)**, a worldwide supplier of semiconductor test and burn-in equipment, today announced it has received over \$2.5 million in production orders for its burn-in and test systems from a leading manufacturer of advanced logic integrated circuits (ICs) for automotive, embedded processing, digital signal processing and analog applications. The orders include down payments to lock in delivery slots and volume pricing discounts.

The orders are for multiple Advanced Burn-in and Test Systems (ABTS™) and a follow-on MAX™ system. The ABTS systems feature a new low-cost high-volume configuration targeted at production test and burn-in of lower-power devices. This new ABTS offers the option of high voltage Device Power Supplies configurable with 60V, 80V, 150V or 230V programmable voltage ranges, which are needed for automotive and power-line applications. Shipments of this new ABTS configuration are expected to begin in the fourth quarter of calendar year 2013.

“We are pleased to receive these orders for production test and burn-in systems,” said Carl Buck, vice president of marketing at Aehr Test Systems. “The new ABTS system configuration offers over 50% more device test capacity than our previous MAX family of production test and burn-in systems. Importantly, this new ABTS is designed to allow the customer to continue to use their extensive inventory of MAX-style burn-in boards on the ABTS while also offering the increased capacity for new devices. This ABTS configuration extends the capabilities of our MAX systems by providing an increase to 128 I/O channels and 8 unique device power supplies per burn-in board, in addition to the new high-voltage supplies.

“The new configuration extends our already successful ABTS-Pi system, which features Individual Temperature Control of each device for high power applications, to provide a lower cost and higher parallel solution for automotive, standard logic and high voltage applications,” Buck concluded.

The ABTS family of products is based on a new hardware and software platform that is designed to address not only today’s devices, but also future devices for many years to come. It can test and burn-in both logic and memory devices, including resources for high pin-count devices and configurations for high-power and low-power applications. The ABTS system can be configured with up to 72 burn-in boards with up to 320 I/O channels each and 32M of test vector memory

per channel. The ABTS system is optimized for use with the Sensata iSocket\* Thermal Management Technology, which provides a scalable cost-effective solution using individual device temperature control for ICs up to 75 watts or more. Individual temperature control enables high-power devices with a broad range of power dissipation to be burned-in simultaneously in a single burn-in chamber while maintaining a precise device temperature. The ABTS system also uses N+1 redundancy technology for many key components in the system to maximize system uptime.

\*iSocket is a trademark of Sensata Technologies, Inc.

### **About Aehr Test Systems**

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS and FOX™ families of test and burn-in systems and the DiePak® carrier. The ABTS system is used in production and qualification testing of packaged parts for both low-power and high-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at [www.aehr.com](http://www.aehr.com).

### **Safe Harbor Statement**

This press release contains certain forward-looking statements based on current expectations, forecasts and assumptions that involve risks and uncertainties. These statements are based on information available to Aehr Test as of the date hereof and actual results could differ materially from those stated or implied due to risks and uncertainties. Forward-looking statements include statements regarding expected initial shipping dates of our ABTS systems. The risks and uncertainties that could cause our results to differ materially from those expressed or implied by such forward-looking statements include, without limitation, general world economic conditions and events, the state of the semiconductor equipment market, our ability to maintain sufficient cash to support operations, acceptance by customers of the ABTS technology, acceptance by customers of the ABTS systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K, 10-Q and other reports from time to time filed with the Securities and Exchange Commission for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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